

Search Notes

Application/Control No.

10/706,757

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

CHOU ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
216	44	3/3/2006	BT
216	53	3/3/2006	BT

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search keywords and inventor's name using USPAT, USPG-PUB, JPO, EPO, DERWENT database	3/3/2006	BT